

**Notice of References Cited**

Application/Control No.

10/663,714

Applicant(s)/Patent Under

Reexamination

INOUE ET AL.

Examiner

AHMED SEFER

Art Unit

2893

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**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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